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(54) POLYMER COMPOUND FOR PHOTORESIST AND PHOTORESIST RESIN COMPOSITION

(57)Abstract:

PROBLEM TO BE SOLVED: To obtain a polymer compound for photoresist excellent in adhesiveness to a substrate and capable of forming fine patterns in good accuracy.

SOLUTION: This polymer compound for photoresist contains at least one species of monomer units selected from monomer units expressed by formula (Ia) and (Ib) (wherein R1, Ra, Rb, Rc, Rd, Re, and Rg are each the same or different and express H or methyl; X1, X2, and X3 are each -CH2- or -CO-Oand at least one of them expresses -CO-O-; m, p and q are each an integer of 0-2).

$$\begin{array}{c}
+CH_2-C \longrightarrow \\
C=0 \\
C=0
\end{array}$$

$$\begin{array}{c}
R^a \longrightarrow X^1 \longrightarrow X^2 \longrightarrow R^c
\end{array}$$

(Ia)

(R^dR^eC) (R^fR⁶)

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